Preferred Device

Sensitive Gate Silicon Controlled Rectifiers

Reverse Blocking Thyristors

Designed primarily for half-wave ac control applications, such as motor controls, heating controls, and power supplies; or wherever half-wave, silicon gate-controlled devices are needed.

Features

- Sensitive Gate Allows Triggering by Microcontrollers and other Logic Circuits
- Blocking Voltage to 800 V
- On-State Current Rating of 8 A RMS at 80°C
- High Surge Current Capability 80 A
- Rugged, Economical TO-220AB Package
- Glass Passivated Junctions for Reliability and Uniformity
- Minimum and Maximum Values of IGT, VGT and IH Specified for Ease of Design
- Immunity to dv/dt 5 V/µsec Minimum at 110°C
- Pb-Free Packages are Available*

MAXIMUM RATINGS (T_J = 25°C unless otherwise noted)

Rating	Symbol	Value	Unit
Peak Repetitive Off–State Voltage (Note 1) (T _J = -40 to 110°C, Sine Wave, 50 to 60 Hz) MCR8SD MCR8SM MCR8SN	V _{DRM} , V _{RRM}	400 600 800	V
On-State RMS Current (180° Conduction Angles; T _C = 80°C)	I _{T(RMS)}	8.0	Α
Peak Non-Repetitive Surge Current (1/2 Cycle, Sine Wave, 60 Hz, T _J = 110°C)	I _{TSM}	80	Α
Circuit Fusing Consideration (t = 8.33 ms)	l ² t	26.5	A ² sec
Forward Peak Gate Power (Pulse Width \leq 10 μ s, T _C = 80°C)	P _{GM}	5.0	W
Forward Average Gate Power (t = 8.3 ms, T _C = 80°C)	P _{G(AV)}	0.5	W
Forward Peak Gate Current (Pulse Width \leq 10 μ s, T _C = 80°C)	I _{GM}	2.0	Α
Operating Junction Temperature Range	T_J	-40 to 110	°C
Storage Temperature Range	T _{stg}	-40 to 150	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

 V_{DRM} and V_{RRM} for all types can be applied on a continuous basis. Ratings apply for zero or negative gate voltage; positive gate voltage shall not be applied concurrent with negative potential on the anode. Blocking voltages shall not be tested with a constant current source such that the voltage ratings of the devices are exceeded.



ON Semiconductor®

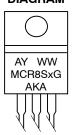
http://onsemi.com

SCRs 8 AMPERES RMS 400 thru 800 VOLTS





MARKING DIAGRAM



TO-220AB CASE 221A-09 STYLE 3

A = Assembly Location

Y = Year
WW = Work Week
x = D, M, or N
G = Pb-Free Package
AKA = Diode Polarity

PIN ASSIGNMENT				
1	Cathode			
2	Anode			
3	Gate			
4	Anode			

ORDERING INFORMATION

Device	Package	Shipping
MCR8SD	TO-220AB	50 Units / Rail
MCR8SDG	TO-220AB (Pb-Free)	50 Units / Rail
MCR8SM	TO-220AB	50 Units / Rail
MCR8SMG	TO-220AB (Pb-Free)	50 Units / Rail
MCR8SN	TO-220AB	50 Units / Rail
MCR8SNG	TO-220AB (Pb-Free)	50 Units / Rail

Preferred devices are recommended choices for future use and best overall value.

^{*}For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

THERMAL CHARACTERISTICS

Characteristic	Symbol	Value	Unit
Thermal Resistance, Junction-to-Case Junction-to-Ambient	$R_{ heta JC} \ R_{ heta JA}$	2.2 62.5	°C/W
Maximum Lead Temperature for Soldering Purposes 1/8" from Case for 10 Seconds	T_L	260	°C

FLECTRICAL CHARACTERISTICS (T. - 25°C unless otherwise noted)

Characteristic			Min	Тур	Max	Unit
OFF CHARACTERISTICS						
Peak Repetitive Forward or Reverse Blocking Current (Note 3) $(V_D = Rated \ V_{DRM} \ and \ V_{RRM}; \ R_{GK} = 1 \ k\Omega)$	T _J = 25°C T _J = 110°C	I _{DRM} , I _{RRM}	_ _	_ _	10 500	μΑ
ON CHARACTERISTICS						
Peak Forward On-State Voltage (Note 2) (I _{TM} = 16 A)		V _{TM}	-	-	1.8	V
Gate Trigger Current (Continuous dc) (Note 4) $(V_D = 12 \ V; \ R_L = 100 \ \Omega)$		I _{GT}	5.0	25	200	μΑ
Holding Current (Note 3) (V _D = 12 V, Gate Open, Initiating Current = 200 mA)		I _H	-	0.5	6.0	mA
Latch Current (Note 4) $(V_D = 12 \text{ V, I}_G = 200 \mu\text{A})$		ΙL	-	0.6	8.0	mA
Gate Trigger Voltage (Continuous dc) (Note 4) $(V_D = 12 \ V; \ R_L = 100 \ \Omega)$	$T_{J} = 25^{\circ}C$ $T_{J} = -40^{\circ}C$	V _{GT}	0.3	0.65 -	1.0 1.5	V
Gate Non-Trigger Voltage $(V_D = 12 \text{ V}, R_L = 100 \Omega)$	T _J = 110°C	V _{GD}	0.2	-	-	V
DYNAMIC CHARACTERISTICS						
Critical Rate of Rise of Off–State Voltage ($V_D = 67\% \ V_{DRM}, \ R_{GK} = 1 \ K\Omega, \ C_{GK} = 0.1 \ \mu F, \ T_J = 110^{\circ}C)$		dv/dt	5.0	15	_	V/μs
Critical Rate of Rise of On–State Current IPK = 50 A, Pw = 40 µsec, diG/dt = 1 A/µsec, lgt = 10 mA		di/dt	-	-	100	A/μs

^{2.} Indicates Pulse Test: Pulse Width \leq 2.0 ms, Duty Cycle \leq 2%.

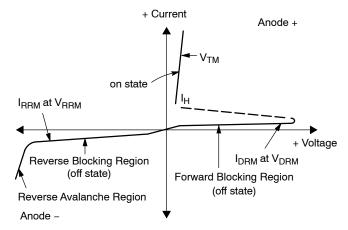
R_{GK} = 1000 Ohms included in measurement.
 Does not include R_{GK} in measurement.

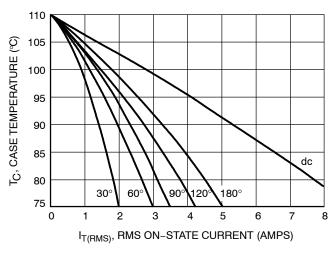
15

100

Voltage Current Characteristic of SCR

Symbol	Parameter
V _{DRM}	Peak Repetitive Off State Forward Voltage
I _{DRM}	Peak Forward Blocking Current
V _{RRM}	Peak Repetitive Off State Reverse Voltage
I _{RRM}	Peak Reverse Blocking Current
V_{TM}	Peak On State Voltage
I _H	Holding Current

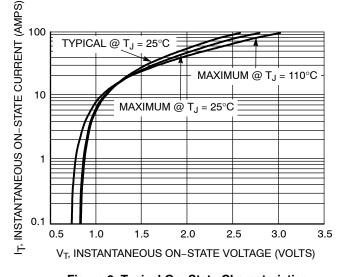




P_(AV), AVERAGE POWER DISSIPATION (WATTS) dc 12 9 180° 120 90° 60° 6 30 3 3 5 $I_{T(AV)}$, AVERAGE ON-STATE CURRENT (AMPS)

Figure 1. Typical RMS Current Derating

Figure 2. On-State Power Dissipation



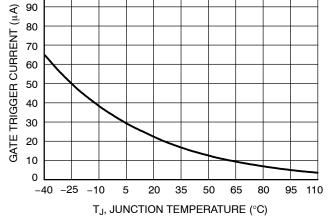
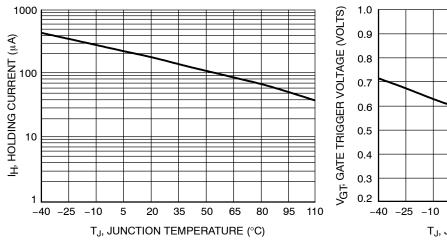


Figure 3. Typical On-State Characteristics

Figure 4. Typical Gate Trigger Current versus **Junction Temperature**



(S) 1.0 0.9 0.8 0.6 0.6 0.5 0.2 -40 -25 -10 5 20 35 50 65 80 95 110 TJ, JUNCTION TEMPERATURE (°C)

Figure 5. Typical Holding Current versus Junction Temperature

Figure 6. Typical Gate Trigger Voltage versus Junction Temperature

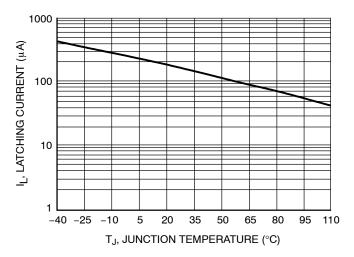
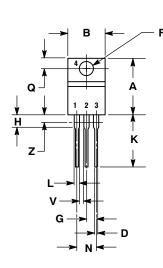
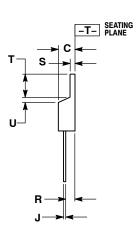


Figure 7. Typical Latching Current versus Junction Temperature

PACKAGE DIMENSIONS

TO-220 CASE 221A-09 **ISSUE AF**





- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
- CONTROLLING DIMENSION: INCH.
 DIMENSION Z DEFINES A ZONE WHERE ALL BODY AND LEAD IRREGULARITIES ARE ALLOWED.

	INCHES		MILLIMETERS	
DIM	MIN	MAX	MIN	MAX
Α	0.570	0.620	14.48	15.75
В	0.380	0.405	9.66	10.28
C	0.160	0.190	4.07	4.82
D	0.025	0.035	0.64	0.88
F	0.142	0.161	3.61	4.09
G	0.095	0.105	2.42	2.66
Н	0.110	0.155	2.80	3.93
J	0.014	0.025	0.36	0.64
K	0.500	0.562	12.70	14.27
L	0.045	0.060	1.15	1.52
N	0.190	0.210	4.83	5.33
Q	0.100	0.120	2.54	3.04
R	0.080	0.110	2.04	2.79
S	0.045	0.055	1.15	1.39
T	0.235	0.255	5.97	6.47
U	0.000	0.050	0.00	1.27
٧	0.045		1.15	
Z		0.080		2.04

PIN 1. CATHODE

- ANODE
- GATE
- ANODE

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